Search Notes



Application/Control No.	Applicant(s)/Patent under
	Reexamination

10/538,715 Examiner TAEYOON KIM FARDEAU ET AL.

Art Unit 1651

SEARCHED			
Class	Subclass	Date	Examiner

Class	Subclass	Date	Examiner

Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
updated search (sequence search: SCORE)	9/4/2008	тк